

IPB80N04S3-H4 IPI80N04S3-H4, IPP80N04S3-H4

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R _{thJC}	-	-	-	1.3	K/W
Thermal resistance, junction - ambient, leaded	R_{thJA}	-	-	-	62	
SMD version, device on PCB	R_{thJA}	minimal footprint	-	-	62	
		6 cm ² cooling area ³⁾	-	-	40	

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	$V_{\rm GS}$ =0 V, $I_{\rm D}$ = 1 mA	40	1	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 65 \mu{\rm A}$	2.1	3.0	4.0	
Zero gate voltage drain current	I _{DSS}	V _{DS} =40 V, V _{GS} =0 V, T _j =25 °C	-	-	1	μΑ
		$V_{\rm DS}$ =40 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C ²⁾	-	-	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =80 A	-	3.9	4.8	mΩ
		$V_{\rm GS}$ =10 V, $I_{\rm D}$ =80 A, SMD version	-	3.6	4.5	

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Dynamic characteristics ²⁾						
Input capacitance	C iss	V _{GS} =0 V, V _{DS} =25 V, f=1 MHz	-	3000	3900	pF
Output capacitance	Coss		1	850	1100	
Reverse transfer capacitance	C _{rss}		-	130	200	
Turn-on delay time	$t_{d(on)}$	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =80 A, $R_{\rm G}$ =3.5 Ω	-	20	-	ns
Rise time	t _r		-	12	-	
Turn-off delay time	$t_{\rm d(off)}$		-	30	-	
Fall time	t _f		-	10	-	
Gate Charge Characteristics ²⁾				1	Γ	
Gate to source charge	Q _{gs}	V _{DD} =32 V, I _D =80 A, V _{GS} =0 to 10 V	-	18	24	nC
Gate to drain charge	Q _{gd}		-	12	18	
Gate charge total	Q _g		-	46	60	
Gate plateau voltage	V _{plateau}		-	5.6	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	-T _C =25 °C	-	-	80	А
Diode pulse current ²⁾	I _{S,pulse}		1	-	320	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =80 A, T _j =25 °C	-	0.95	1.3	V
Reverse recovery time ²⁾	t _{rr}	V_{R} =20 V, I_{F} = I_{S} , di_{F}/dt =100 A/ μ s	-	35	-	ns
Reverse recovery charge ²⁾	Q _{rr}		-	35	-	nC

 $^{^{1)}}$ Current is limited by bondwire; with an $R_{\rm thJC}$ = 1.3K/W the chip is able to carry 119A at 25°C.

²⁾ Defined by design. Not subject to production test.

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



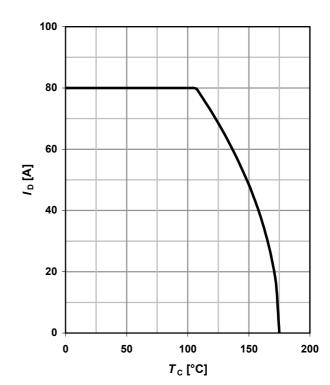
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$

100 80 80 40 20 0 0 0 0 100 150 200 T_C [°C]

2 Drain current

$$I_D = f(T_C); V_{GS} \ge 6 \text{ V}$$



3 Safe operating area

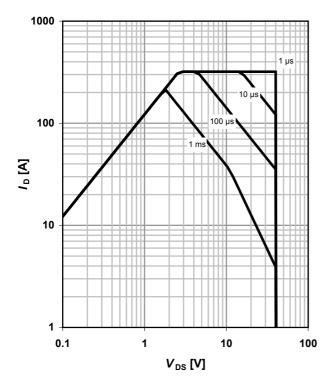
$$I_D = f(V_{DS}); T_C = 25 \degree C; D = 0; SMD$$

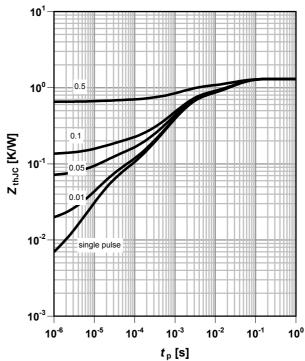
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\rm thJC} = f(t_{\rm p})$$

parameter: $D = t_p/T$



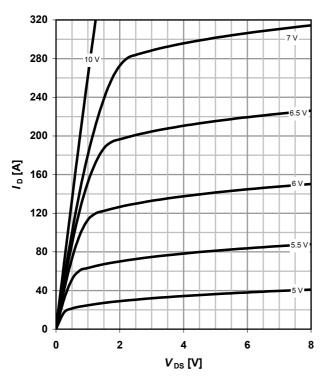




5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C; SMD$

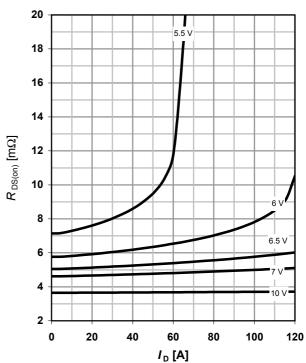
parameter: V_{GS}



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}; SMD$

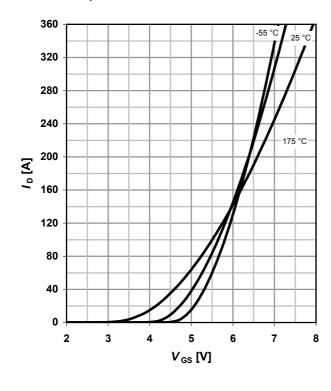
parameter: V_{GS}



7 Typ. transfer characteristics

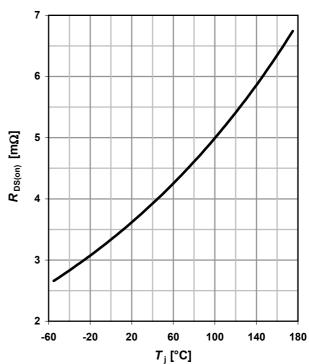
 $I_D = f(V_{GS}); V_{DS} = 6V$

parameter: T_i



8 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(T_j); I_D = 80 \text{ A}; V_{GS} = 10 \text{ V}; \text{SMD}$





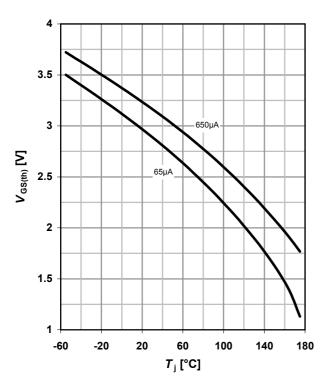
9 Typ. gate threshold voltage

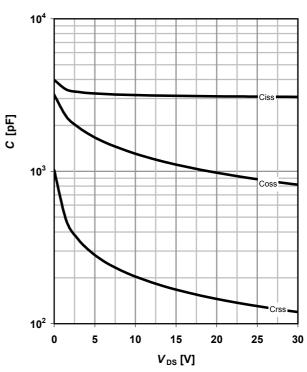
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristicis

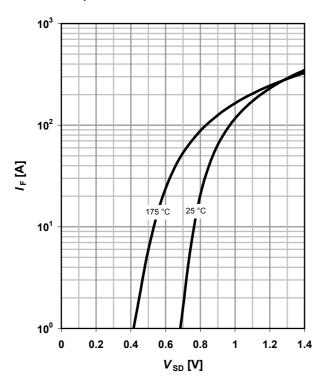
 $IF = f(V_{SD})$

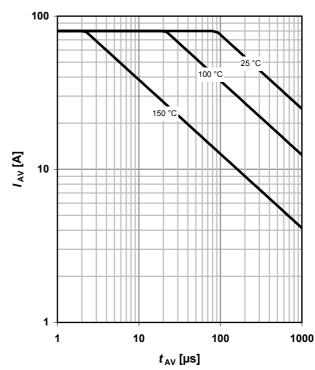
parameter: T_i

12 Typ. avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}







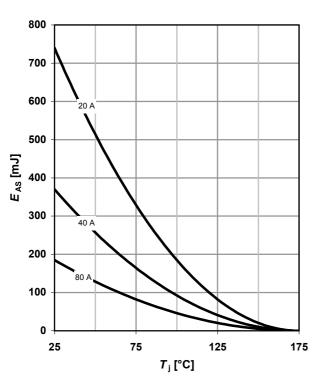
13 Typical avalanche energy

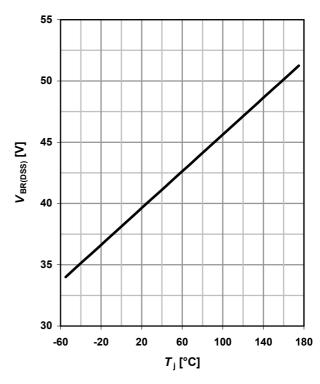
 $E_{AS} = f(T_i)$

parameter: $I_{\rm D}$

14 Typ. drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$

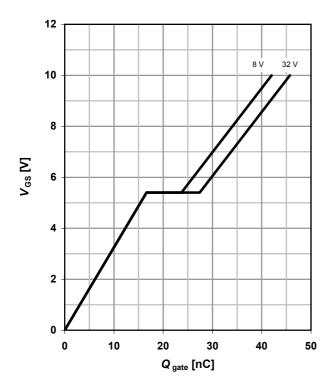




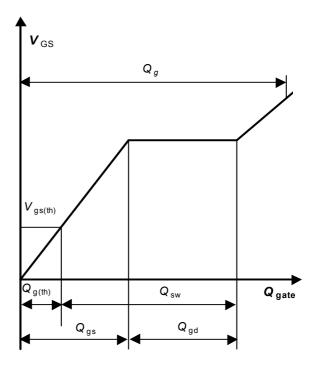
15 Typ. gate charge

 $V_{\rm GS}$ = f($Q_{\rm gate}$); $I_{\rm D}$ = 80 A pulsed

parameter: $V_{\rm DD}$



16 Gate charge waveforms





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Revision History

Version	Date	Changes			